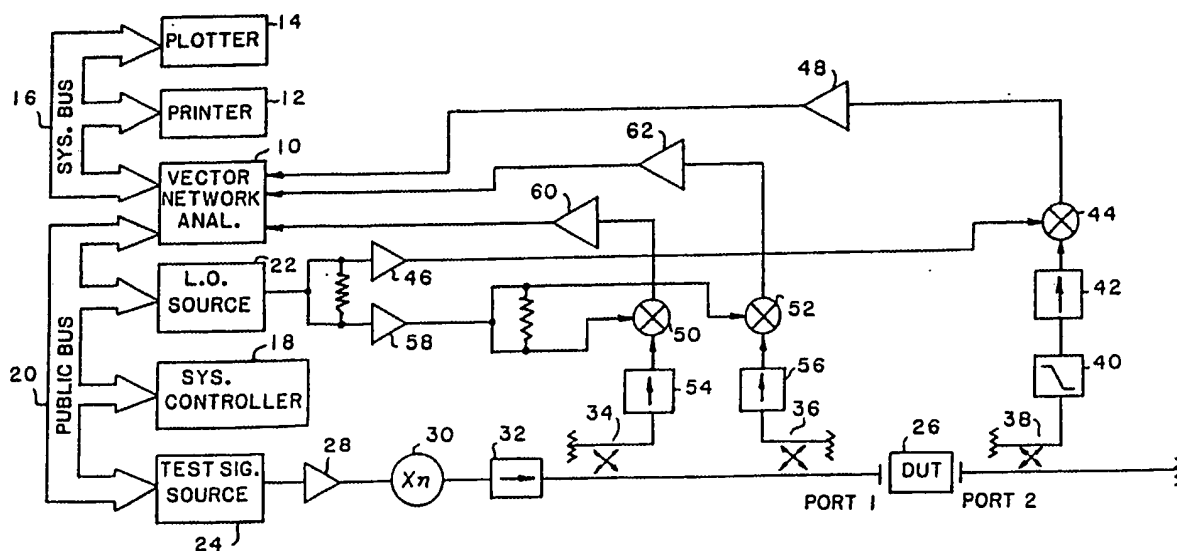


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(54) Title: CALIBRATING METHOD FOR APPARATUS EVALUATING MICROWAVE/MILLIMETER WAVE CIRCUITS



A calibration procedure for vector network analyzers utilizing a known standard, an unknown standard and a pair of offsets bearing a known length ratio (2:1) between them whereby measurements taken on the standards and their combinations with the offsets result in self-verifying redundant equations which furnish: (1) error terms according to well-known flow graph models, (2) the reflection of the unknown standard, (3) the transmission factor of the waveguiding medium from which the offsets are realized regardless of the waveguide's loss or dispersion, and (4) a figure of merit (corruption coefficient) for the quality of the acquired raw data without the necessity for computing the error terms, connecting verification standards or otherwise completing the calibration process.

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CALIBRATION METHOD FOR APPARATUS EVALUATING
MICROWAVE/MILLIMETER WAVE CIRCUITS

Background of the Invention

This invention relates to a calibration method and more particularly to a method for calibrating apparatus, such as a vector network analyzer, utilized for making
5 evaluations of circuits operating at microwave and millimeter wave frequencies.

Most calibration methods used for electronic measurement apparatus require the use of a set of extremely high quality standards whose characteristics are known in
10 advance. Additionally, a well known standard must be connected to verify the calibration procedure. Before any vector network analyzer system utilized for measuring the characteristic of devices can be used, it must be calibrated to remove any systematic errors in the
15 measurement hardware. Accordingly, conventional calibration techniques at microwave or millimeter wave frequencies demand the fabrication of precise short circuits, open circuits and matched loads which need to be fabricated to exacting tolerances, not easily achieved. Moreover, such
20 methods are inhibited by dispersion in the transmission medium, for example, microstrip, slotline, coplanar line, coplanar strips, etc. in which the measurement is performed. These dispersion characteristics are often unknown in millimeter wave integrated circuit devices
25 thereby further compounding measurement difficulty. Also, the integrity of the operation hinges very critically on whether ideal electrical characteristics are reproduced at the launch plane for every calibration and verification device and for the device under test. Thus, conventional
30 techniques do not furnish a convenient method for assessing the uncertainties due to variations in such characteristics.

A typical prior art calibration technique is disclosed

in an article entitled, "Calibration of an Automatic Network Analyzer Using Transmission Lines of Unknown Characteristic Impedance, Loss and Dispersion", by E. F. daSilva et al. appearing in The Radio and Electronics Engineer, Vol. 48, No. 5, pp. 227-234, May, 1978.

It is an object of this invention, therefore, to provide an improved method for calibrating electronic measurement apparatus.

It is another object of this invention to provide an improved method for calibrating network analyzers for evaluating conventional and integrated circuits operating at microwave and millimeter wave frequencies.

It is still another object of this invention to provide an improved method for calibrating network analyzers by employing measurement redundancy to enhance stability, convergency, and accuracy of the measurements.

It is a further object of this invention to provide a method for calibrating vector network analyzers by utilizing relative characteristics among standards as opposed to their absolute characteristics.

It is yet a further object of this invention to provide a method for calibrating vector network analyzers which yields a direct and convenient measure of calibration quality.

It is still a further object of this invention to provide a self-verifying method for calibrating vector automatic network analyzers.

Summary

Briefly, the foregoing and other objects of this invention are provided by a method which determines the systematic errors associated with millimeter wave vector network analyzers utilized to measure complex reflection and transmission coefficients or impedance characteristics of components and devices used in microwave/millimeter wave waveguides or transmission lines. The method uses redundancy of measurements and relative characteristics to furnish information to indicate the level of non-

correctable corruption entering into the calibration procedure due to random errors. Also, as a part of the calibration procedure according to the present invention, there is provided a determination of the propagation
5 properties of the transmission medium such as loss and dispersion.

Ratios of the respective lengths of transmission line offsets coupled to a measurement port of a vector network analyzer provide a means to generate independent
10 measurement conditions without the need for independent high quality standards. The method is thus not restricted by dispersion, losses or the lack of a plurality of high quality standards.

In the illustrated embodiment detailed below, the
15 calibration procedure is controlled by a microprocessor and involves storing data for measurements taken via the network analyzer for a plurality of frequencies swept over a frequency range for six different circuit elements coupled to the measurement port of the vector network
20 analyzer, namely, a load, an offset load, a doubly offset load, a short, an offset short, and a doubly offset short. Neither the offset nor the load need to be known a priori. They are determined by the calibration algorithm which also furnishes the usual error terms i.e. source match,
25 directivity, frequency response tracking, etc. The value of load and/or offset as calculated by the procedure can be compared against an actual measurement of that component by the network analyzer to derive verification of the calibration.

30 Brief Description of the Drawings

The objects of the present invention and the attendant advantages thereof will become apparent by reference to the following drawings, wherein:

Figure 1 is an electrical block diagram of a vector
35 network analyzer system utilized in practicing the method according to the subject invention;

Figures 2A and 2B are electrical schematic diagrams

illustrative of standard error models for one-port and two-port devices;

Figure 3 is a polar representation indicating the corruption factor for a typical calibration run utilizing the apparatus shown in Figure 1;

Figure 4 is a polar representation indicating the corruption factor obtained when time for instrument warm-up was not adequate;

Figure 5 is a polar representation indicating the corruption factor for a calibration procedure when using a sliding load to produce offset load conditions;

Figure 6 is a unit circle diagram helpful in understanding the method according to the subject invention;

Figure 7 is a polar representation of the magnitude and phase of an offset short calculated from the procedure;

Figures 8A and 8B are characteristic curves illustrative of the magnitude and phase of a source match error coefficient obtained by the subject invention;

Figures 9A and 9B are characteristic curves illustrative of the magnitude and phase of a reflection tracking coefficient obtained by the subject invention;

Figures 10A and 10B are characteristic curves illustrative of the magnitude and phase of a directivity error coefficient obtained by the subject invention;

Figures 11A and 11B are characteristic curves illustrative of the standing wave ratio and return loss representation of a reflection coefficient obtained by the subject invention;

Figure 12 is a polar representation of the impact of corruption on a reflection coefficient obtained by the subject invention;

Figure 13 is an illustrative curve of the impact of corruption shown in a log magnitude format on a reflection coefficient obtained by the subject invention; and

Figure 14 is a polar representation similar to Figure 12 and being illustrative of the impact of corruption on an

offset short connected to the apparatus of Figure 1.

Detailed Description

Referring now to Figure 1, there is shown a typical vector network analyzer system for evaluating millimeter wave circuit components and including a vector network analyzer 10 comprising, for example, a Hewlett-Packard HP8510 network analyzer. The vector network analyzer 10 is coupled to a printer 12 and a plotter 14 by means of a digital bus 16 designated a system bus. The network analyzer 10, moreover, is controlled by a system controller 18 comprising a microprocessor. The microprocessor 18 is coupled to the vector network analyzer 10 through a second digital bus termed a public bus which is also connected to a local oscillator source 22 and a test signal source 24 whose frequency and power output is controlled by the microprocessor.

The system as shown comprises a two port network to which is coupled a device under test (DUT) 26. One port, port 1, is coupled to a millimeter wave frequency signal through an amplifier 28 coupled to the test signal source 24 which has been multiplied by a factor of X2 or X3 by a frequency multiplier 30 which is then connected to port 1 through a signal isolator 32 and a pair of millimeter wave signal couplers 34 and 36. The second measurement port, designated port 2, comprises an output port which is coupled back through the vector network analyzer 10 through a third millimeter wave coupler 38, bandpass filter 40, an isolator 42 and a signal mixer 44. The mixer 44 is coupled back to the local oscillator source 22 by means of an amplifier 46. The output of the mixer 44 couples back to the vector network analyzer 10 by way of an amplifier 48. The multiplied output frequency of the test signal source 24 is also fed to a pair of signal mixers 50 and 52 which are respectively coupled to the couplers 34 and 36 via the isolators 54 and 56. Mixers 50 and 52 also receive a local oscillator input from the local oscillator source 22 by way of amplifier 58. The output of the mixers 50 and 52 are

coupled back to the vector network analyzer 10 by way of a pair of amplifiers 60 and 62. A typical one port calibration procedure involves connecting a plurality of standards to port 1 whereupon the system operates as a
5 reflectometer.

The system controller includes software which sets the test signal source 24, then the local oscillator source 22 and when the system has settled makes the measurement and plots the data in a user-prescribed format on a CRT screen,
10 not shown, associated with the vector network analyzer 10. This sequence is repeated for each of 51, 101, 201 or 401 points over a selected frequency range in a well known manner for the test apparatus represented in Figure 1.

Conventional one port calibration methods involving
15 vector network analyzers such as shown in Figure 1 demand the fabrication of precise short circuits and matched loads, all to exacting tolerances often beyond the reach of current state-of-the-art monolithic fabrication techniques. This also applies to known two-port calibration methods.
20 Further, such techniques are inhibited by dispersion in the transmission medium, e.g., microstrip, slot line, coplanar line, coplanar strips, etc. These dispersion characteristics are often unknown in the integrated circuit environment, thereby further compounding
25 measurement difficulty. Also, the integrity of a calibration of the vector network analyzer hinges very critically on whether identical electrical characteristics are reproduced at the launch plane (Port 1) for every calibration and verification device and for the device
30 under test. Thus, state-of-the-art techniques do not furnish a convenient method for assessing the uncertainties due to variations in such characteristics. Unfortunately, integrated circuit technology is very prone to deficiencies arising from launch plane integrity, thus leading to poor
35 confidence in the quality of calibrations. Finally, the conventional approach of verifying a calibration by inserting a separate verification device assumes good

launch plane integrity for the verification standard. This has been found to be a poor assumption for the integrated circuit environment.

The present invention overcomes these limitations by capitalizing on the strengths of integrated circuit fabrication. For example in such fabrication, it is easier to hold parameter ratios to tight tolerances rather than the discrete values of the parameters themselves. This invention, as will be shown, is well suited for such a condition because, as the following example will show, it is based on the use of ratioed lengths of transmission line offsets coupled to the measurement port, i.e. Port 1 of Figure 1. The algorithm to be described herein furnishes the transmission line's loss and dispersion characteristics as part of the calibration procedure, a decided advantage for integrated circuit evaluation. This invention also reduces the need for simultaneously maintaining extremely tight tolerances over a range of calibration device types. Instead, it can be applied based on a priori knowledge of only one standard type, e.g. a short circuit, so that only the assumed characteristics of this type of standard must be met in production. All the other standards are determined relative to this one standard (short) as part of the calibration procedure, and therefore can have an arbitrary tolerance. For these standards, however, the technique relies on the reproducibility of the integrated circuit environment.

Lastly, this invention integrates calibration and verification to produce three desirable outcomes: (1) a measure of the corruption that entered into the calibration without the necessity of completing the process, (2) a quantitative display of the uncertainty limits for the calibration/verification procedure, and (3) a basis for inserting automation into the calibration process. The first outcome allows the user to abort a given calibration run because of the poor quality of the acquired raw data without ever having to compute the calibration

coefficients. The second gives the user an immediate estimate of the quality of the calibration, and the third provides a natural basis for artificial intelligence automation of the procedure so that high throughput, vital for reducing integrated circuit costs, is possible.

As in other known prior art calibration techniques, the method of the subject invention exploits the usual transformation property of a terminated transmission line. More specifically, standard transmission line theory predicts that a load (L) with an inherent reflection coefficient of Γ will transform to a reflection coefficient Γ_L as:

$$\Gamma_L(\ell) = \Gamma e^{-2\gamma\ell} = \Gamma z^{-1} \quad (1)$$

when measured through a length (ℓ) of transmission line. In general, all the Γ s are complex numbers, i.e. having both a magnitude and a phase. As defined above, $z = e^{2\gamma\ell}$, where γ is the complex propagation factor for the transmission line, and $\gamma = \alpha + j\beta$, where α is the line's attenuation constant and β is its phase constant.

With the foregoing in mind, this invention is based on well known standard error models represented by signal flow graphs (Figures 2A and 2B) with coefficients expressed as frequency response tracking E_R or E_T , directivity E_D , source match or load match E_S or E_L and isolation E_X . These error terms are determined by calibration, and are alternatively called calibration coefficients or error coefficients. In addition to these error coefficients the propagation factor z of the transmission line and the reflection coefficient Γ_L of at least one other standard such as a load must be determined. Thus, there are five unknowns and, therefore, five independent measurements are needed.

The use of offset lengths of transmission line offers a convenient way to generate independent measurement conditions without the need for independent standard types.

For example, adding an offset length (ℓ) of transmission line to a short circuit ($\Gamma_{\text{short}} = -1$) creates a new measurement of an "offset short", provided the larger offset length is less than a half wavelength at the highest frequency of interest. It must be less than a quarter wavelength if the known standard is a short (open) and the unknown is an open (short). In the present invention technique, two offsets of lengths (ℓ) and (2ℓ) are used. The ratio of the lengths, i.e., 2:1, is of greater importance to the technique's success than the actual value of (ℓ).

If these offset lengths are combined with the short circuit, three measurement conditions are generated which can be concisely represented by the expression:

$$C_{Sn} = E_D - \frac{E_R}{z^n + E_S} \quad (2)$$

where C_{Sn} is the raw or measured data value of the reflection coefficient $\Gamma_S = -1$, $n=0$ corresponds to a short, $n=1$ corresponds to an offset short, and $n=2$ corresponds to a doubly-offset short. The flow diagrams of Figures 2A and 2B contain the prescription for obtaining the expressions for Equations 2 and 3 as is well known in the art.

A similar expression C_{Ln} can be developed for an arbitrary load that is different from the short and its combination with the same $n=1$ and $n=2$ offsets, namely,

$$C_{Ln} = E_D + \frac{E_R \Gamma_L}{z^n - E_S \Gamma_L} \quad (3)$$

Expressions (2) and (3) thus provide equations for C_{S0} , C_{S1} , C_{S2} , and C_{L0} , C_{L1} , C_{L2} which can be used for determining the five above identified unknowns of E_R , E_D , E_S , z , and Γ_L . However, the six equations may be used to eliminate all the unknowns from the measurement set, so that a relationship can be developed relating to the raw or measured data values only. For the particular case of the

- 10 -

instant example, this relationship is:

$$K_L = \frac{K_{LS}^{20}}{K_S} \quad (4)$$

where

$$K_L = \frac{C_{L2} - C_{L1}}{C_{L1} - C_{L0}} \quad (5)$$

$$K_{LS}^{20} = \frac{C_{L2} - C_{S2}}{C_{L0} - C_{S0}} \quad (6)$$

$$K_S = \frac{C_{S2} - C_{S1}}{C_{S1} - C_{S0}} \quad (7)$$

Equation (4) forms the basis for defining a corruption factor, K_{Cor} as

$$K_{Cor} = K_L - \frac{K_{LS}^{20}}{K_S} \quad (8)$$

If the errors occurring during calibration were solely systematic, then Eq. (4) would be satisfied exactly and $K_{Cor} = 0$.

In practice, however, non-systematic errors arising from noise, drift, cable stability, connector repeatability, spurious responses, etc., will generally cause K_{Cor} to have a non-zero value. When a calibration was performed on a vector network analyzer system as shown in Figure 1 and including a Hewlett-Packard (HP) model R11643A Ka-band extender test set in conjunction with a HP 8510A vector network analyzer, the distribution of K_{Cor} over a 26.5 GHz to 40 GHz frequency range on a polar display as shown in Figure 3 directly indicates the extent to which the integrity of the calibration is compromised. The farther away from the origin the distribution, the poorer the integrity of the calibration.

K_{Cor} shows very strong correlation with non-correctable errors. For example, Fig. 4 shows K_{Cor} for a calibration performed on the same vector network analyzer system as shown in Figure 1 immediately after power turn-on, i.e., without allowing sufficient time for the instrument to stabilize. Figure 5 illustrates the effect of connector repeatability on the corruption factor and is distinguished from Fig. 3 in that the offset loads were produced by using a micrometer adjustment on a sliding load instead of by way of waveguide shims.

Unlike conventional methods, information about corruption in the raw data is available by this invention immediately after data acquisition and does not require a calibration, i.e., determination of the error terms referred to above, to be completed. Thus, a user may reject an excessively corrupted data set by aborting a calibration run early in its cycle. In an automated environment, measurement throughput will thus be increased because of the early detection and rejection of corrupt data sets.

At this point, redundant measurement is exploited to obtain an algorithm with superior numerical stability and convergence properties even at relatively high corruption levels, a distinct advantage and improvement as it relates to use in connection with millimeter wave integrated circuit testing. The calibration method produces stable outputs, e.g., offset z , load reflection Γ_L , and the error coefficient terms, even though its inputs, namely the raw data, have fluctuations arising from corruption. Numerical stability is achieved by anticipation of the distribution of the raw data on a polar diagram plot and their susceptibility to corrupting influences from signal-to-noise considerations and recognizing that the calculations involve ratios of vector differences between the points that represent the raw data. Thus, vector differences between points that are closely spaced relative to the fluctuation in the position of those points will be very

sensitive to those fluctuations and must be avoided. Using redundancy is key to providing the flexibility for such avoidance. Convergence is manifested by the agreement of the determined quantities with their actual or true values.

- 5 The equations represented by (2) and (3) can be used to eliminate all the E's and \bar{T}_L , so that the relationship between the raw data and the offset z can be expressed as:

$$z^2 - C_z + 1 = 0 \quad (9)$$

- 10 The constant C , in Equation 9, is a function of the raw data C_{Sn} and C_{Ln} and can be expressed as such, in a number of mathematically equivalent forms. However, because the raw data is corrupt, certain functional forms are preferred because they are less sensitive to corrupting influences. Accordingly, C is expressed as:

15
$$C = K_{LS}^{10} \left(1 + \frac{1}{K_S} \right) \left(1 + \frac{K_S}{K_{LS}^{20}} \right) - 2 \quad (10)$$

where

$$K_{LS}^{10} = \frac{C_{L1} - C_{S1}}{C_{L0} - C_{S0}} \quad (11)$$

- and the other constants have been defined previously. The expression for C in Eq. (10) has been derived in part by using Eq. (4) and the knowledge that K_L as defined in Eq. (5) is more susceptible to corruption when \bar{T}_L is a load than are either K_S or K_{LS}^{20} . This is one example of how redundant measurement is exploited as asserted above. Equation (9) can be solved to obtain the two roots, z_+ and z_- , where
- 25

$$z_{\pm} = \frac{C \pm \sqrt{C^2 - 4}}{2} \quad (12)$$

A number of important observations can be made regarding the roots. From the theory of quadratic equations,

13

$$z_+ \cdot z_- = 1 \quad (13)$$

and

$$z_+ + z_- = C \quad (14)$$

5

Equation (13) suggests that the two roots must be phase conjugate, or, more generally, $\arg(z_+) + \arg(z_-) = 2m\pi$, where $m = 0, 1, 2, 3, \dots$. Also, if the magnitude of any one of the roots is greater than unity, the other root must have a magnitude less than unity. These conditions are illustrated in Fig. 6. According to Eq. (1), the root that corresponds to attenuation, due to line loss, has a magnitude greater than unity, and is therefore the correct root. In the absence of line loss, the two roots must have unit magnitude and be complex conjugates of each other. For this case, Eq. (14) implies that C is real. Thus, the imaginary part of C is a sensitive indicator of transmission line losses and also corruption. These conclusions, however, are not obvious from equation 10 for the expression for C .

Once z is determined, its reciprocal is the transformation factor for the single offset according to Eq. (1), and, in particular, $-z^{-1}$ represents the reflection of the offset short as displayed in Fig. 7, which represents the magnitude and phase of the offset short after the correct root is chosen.

The source match error coefficient E_s is next calculated from the previously determined z (Eq. 13), K_s (Eq. 8), and the formula

30

$$E_s = - \frac{z(1 - zK_s)}{z - K_s} \quad (15)$$

derived from Eq. (2). The result is displayed in Figs. 8a

and 8b which disclose the magnitude and phase of the source match.

Eq. (2) may be manipulated to derive the reflection tracking error coefficient E_R which can be expressed as:

5

$$E_R = \frac{(1 + E_s)(z + E_s)(C_{s1} - C_{s0})}{z - 1} \quad (16)$$

and is shown in Figs. 9a and 9b.

Next, the directivity error coefficient, E_D , may be
10 obtained from Eq. (2) with $n = 0$, as:

$$E_D = C_{s0} + \frac{E_R}{1 + E_s} \quad (17)$$

and is illustrated in Figs. 10a and 10b.

Once the error coefficients E_S , E_R and E_D are determined, the reflection coefficient Γ_L of the load can
15 be determined from Eq. (3) with $n = 0$, as:

$$\Gamma_L = \frac{(C_{L0} - E_D)}{(C_{L0} - E_D)E_s + E_s} \quad (18)$$

The load reflection is shown in the standing wave ratio and return loss curves of Figs. 11a and 11b, respectively.

Up to this point, all of the primary parameters have
20 been determined, namely, the errors terms, the reflection coefficient of the load Γ_L , and the offset z , and K_{Cor} has provided a measure of the corruption in the calibration process. However, the relationship between the displayed value of corruption, K_{Cor} and confidence in the calibration
25 procedure has not yet been established.

Because there are six measurement conditions, the obvious verification strategy would be to use any five of them to determine the unknowns identified above, and the sixth relation to verify the calibration. However, such an
30 algorithm is practical only for highly sanitized raw data.

Greater numerical stability of the algorithm results from developing the error terms described above and using the approach now to be described.

Any number of the six measurement conditions may be used to assess the effect of the corruption factor, K_{Cor} on the calibration. Because the reflection coefficient of the load Γ_L and offset z are outputs of the procedure, the offset short and the load measurement are recommended for the assessment, thus allowing the effect of K_{Cor} to be determined at the two extremes of the dynamic range of the measuring apparatus.

Equation (4) becomes a starting point for making assessments of corrupting influences on all terminations. In particular, it can be used to solve for the raw data of the load termination, i.e., C_{L0} , in terms of the other raw data. The result is

$$C_{L0} = \frac{C_{L1} + \frac{(C_{L2} - C_{L1})}{(C_{L2} - C_{S2})} K_S C_{S0}}{1 + \frac{(C_{L2} - C_{L1})}{(C_{L2} - C_{S2})} K_S} \quad (19)$$

The equality of Eq. (19) holds only in the absence of non-systematic (i.e., corrupting) influences. The right-hand side of equation 19 may therefore be viewed as an alternate representation of C_{L0} , which approaches the actual measured raw coefficient in the limit of zero corruption. Thus, both sides of Eq. (19) can be substituted in Eq. (18) to determine the corresponding Γ_L . On the HP 8510A, vector analyzer 10 (Figure 1) the value of Γ_L corresponding to the right-hand side of Eq. (19) is stored in memory and the actual load reflection (left-hand side) is viewed as data after the correction is applied. This procedure is executed with the load connected .

A very sensitive indication of the impact of corruption is now obtained by dividing the two values of Γ_L . In the absence of corruption, the resulting display is a single point located at (1, 0) on a polar display.

Corruption will cause "smearing" of the point as Figure 12 illustrates for an actual load verification; Fig. 13b presents the data of Fig. 12 in log magnitude format, and Fig. 11 shows the actual return loss. The agreement is
 5 within ± 0.5 dB for a return loss in excess of 35 dB over the entire Ka band.

The same procedure could be applied to an offset short. However, an alternate method is available based on the calculated offset z since the offset short can be
 10 represented by the left and right hand sides of the equality:

$$-z^{-1} = \frac{C_{s1} - E_D}{(C_{s1} - E_D)E_s + E_R} \quad (20)$$

which holds true when corruption is absent. Alternatively, the value of the offset short can be evaluated by
 15 substituting its raw measurement C_{s1} and the computed error terms (Eqs. 15 through 18), into Eq. (2) with $n = 1$, and comparing the resulting estimate with the previous representation. On dividing one by the other, a single point results (Fig. 13) in close proximity to (1, 0). In
 20 practice, the trace ratios are always less than ± 0.005 dB (0 dB in a perfect system) in magnitude, and the angular elevation from the real axis is less than $\pm 0.8^\circ$ (0° in a perfect system). Better phase stability will be obtained if the ambient temperature is controlled. In the same
 25 manner, a comparison can be made for a doubly offset short by testing for the equality as represented by the expression:

$$-z^{-2} = \frac{C_{s2} - E_D}{(C_{s2} - E_D)E_s + E_R} \quad (21)$$

and for a simple short with no offset it can be determined
 30 by testing the equality:

$$-1 = \frac{C_{s0} - E_D}{(C_{s0} - E_D)E_R - E_R} \quad (22)$$

Thus the corrupting influences can be determined by testing the equalities as expressed in equations (20, 21 and 22).

Comparing the ± 0.5 dB uncertainty (Fig. 12) for the load measurement with the ± 0.005 dB uncertainty (Fig. 13) for the short indicates that corruption has less influence on the short than on the load. This is to be expected if the chief corrupting influence is connection interface non-reproducibility. In practical measurement situations, discontinuities at the interconnect will produce small reflection amplitudes that will have a more pronounced influence on the low-level reflection emanating from a load than on the much larger reflection signal returned by the short. Nevertheless, this verification step for the offset short is strongly recommended for detecting gross operator-induced flaws during calibration.

Although an algorithm for assessing the effect of K_{Cor} on the calibration has been described, this specification is incomplete without a comparison of the calibration's outputs with the true values of the corresponding quantities, e.g., how close the offset is to its "true" value. In the foregoing example where a calibration is implemented in WR-28 rectangular waveguide using the dominant TE_{10} mode, standard waveguide theory may be used to predict the true value of offset at each frequency. For an actual calibration run utilizing a system such as shown in Figure 1, the calculated offset values are 104.1° at 26.5 GHz and 20° at 40 GHz for the particular offset length (1.956 mm for the smaller offset) used, while the corresponding measured values (Fig. 5) are 103.89° and 19.3° , respectively. In actual experience, measured deviations were smaller than 3° even when K_{Cor} was relatively large.

Thus, the method of the subject invention involves: (a) acquiring and storing raw data for the measurement conditions involving at least one known standard such as a short and its associated combinations of an offset short and doubly offset short and an unknown standard differing

from the known standard such as a load, offset load, and a doubly-offset load; (b) determining, by means of software the corruption factor K_{Cor} in accordance with equation (8) and the factors of the raw data expressed in equations (5) through (7); (c) determining the offset z from equation (9) taking into account the factors expressed in equations (4), (10) and (11); (d) finding the roots of the offset z in accordance with equation (12) which will provide an offset value for z ; (e) calculating the source match, E_S , from equation (15); (f) calculating the reflection tracking coefficient, E_R , in accordance with equation (16); (g) calculating the directivity, E_D , in accordance with equation (17); (h) calculating the reflection coefficient, Γ_L , in accordance with equation (18); (i) determining the corrupting influences on all terminations particularly the load termination C_{L0} in accordance with equation (19); and (j) and displaying the results on the network analyzer as set forth above.

There are significant benefits to having a calibration procedure in which the load, Γ_L , does not need to be known a priori. For example, one may use the device on which measurement is ultimately desired (and for which the instrument is being calibrated in the first place) as the "load". The procedure will then determine its reflection coefficient. Another significant example is one where the return port, i.e. port 2 of Figure 1 is used in place of Γ_L . In this case, the load match error term, E_L , is determined by the method set forth above. The other two-port error terms may be obtained by combining this technique with other conventional methods.

Having shown and described what is at present considered to be the preferred method calibration, it should be known that the same has been made by way of illustration and not limitation. Accordingly, all modifications, alterations and variations coming within the spirit and scope of the invention as set forth in the appended claims are meant to be included.

Claims:

1. A method for calibrating measurement apparatus such as a vector network analyzer for making evaluations of circuits operating at microwave and millimeter wave frequencies comprising the steps of:
- 5 (a) acquiring and storing data for measurement conditions involving an arbitrary known standard termination alone and in combination with a ratioed length pair of offsets;
- 10 (b) acquiring and storing data for measurement conditions involving an unknown standard termination different from the known standard termination alone and in combination with a pair of offsets having the same length ratio as set forth in step (a);
- 15 (c) determining a figure of merit of the quality of the acquired raw data;
- (d) determining the value of the offsets used in steps (a) and (b);
- (e) determining a plurality of predetermined error terms or coefficients;
- 20 (f) determining the reflection coefficient of the unknown standard; and
- (g) determining the corrupting influences on said terminations by comparison of their calculated values as determined in steps (d) and (f) with their measured values.
- 25 2. The method as defined by claim 1, wherein the known standard comprises a short circuit, an open circuit, or a termination with known but arbitrary response.
- 30 3. The method as defined by claim 1 wherein the unknown standard comprises a load, a short circuit, an open circuit, or other termination with unknown and arbitrary response different from the response of said known standard.

4. The method as defined by claim 1 wherein said offsets have a length ratio of 2:1.

5. The method as defined by claim 1 wherein said figure of merit of step (c) comprises the corruption factor
5 K_{Cor} .

6. The method as defined by claim 1 wherein said error coefficients include frequency response tracking, E_R , directivity, E_D , and source match, E_S , and/or load match, E_L .

10 7. The method as defined by claim 6 wherein said error coefficients additionally include isolation, E_X , and transmission tracking, E_T .

8. The method as defined by claim 1 wherein said figure of merit of step (c) comprises the corruption factor
15 K_{Cor} which is expressed as:

$$K_{Cor} = K_L - \frac{K_{LS}^{20}}{K_S}$$

where

$$K_L = \frac{C_{L2} - C_{L1}}{C_{L1} - C_{L0}}$$

$$K_{LS}^{20} = \frac{C_{L2} - C_{S2}}{C_{L0} - C_{S0}}$$

and

$$K_S = \frac{C_{S2} - C_{S1}}{C_{S1} - C_{S0}}$$

where C_{S0} , C_{S1} , C_{S2} , C_{L0} , C_{L1} and C_{L2} comprises measured data values of the reflection coefficients for a short, doubly offset short, doubly offset short, a load, offset load, and doubly offset load, respectively.
20

9. The method as defined by claim 8 where said step (d) comprises determining the offset z from the roots of the expression:

$$z^2 - C_z + 1 = 0$$

where

$$C = K_{LS}^{10} \left(1 + \frac{1}{K_S} \right) \left(1 + \frac{K_S}{K_{LS}^{20}} \right) - 2$$

and

$$K_{LS}^{10} = \frac{C_{L1} - C_{S1}}{C_{L0} - C_{S0}}$$

10. The method as defined by claim 9 wherein said roots are expressed as:

$$z_{\pm} = \frac{C \pm \sqrt{C^2 - 4}}{2}$$

- 5 11. The method as defined by claim 10 and wherein one of the error coefficients of step (e) comprises the source match, E_S , which is determined by the expression:

$$E_S = - \frac{z(1 - zK_S)}{z - K_S}$$

12. The method as defined by claim 11 wherein one of the error coefficients of step (e) comprises the reflection
10 tracking error coefficient, E_R , which is determined by the expression:

$$E_R = \frac{(1 + E_S)(z + E_S)(C_{S1} - C_{S0})}{z - 1}$$

13. The method as defined by claim 12 wherein one of the error coefficients of step (e) comprises the directivity error coefficient, E_D , which is determined by
15 the expression:

$$E_D = C_{S0} + \frac{E_R}{1 + E_S}$$

14. The method as defined by claim 13 wherein said

step (f) of determining the reflection coefficient Γ_L , in accordance with expression:

$$\Gamma_L = \frac{(C_{L0} - E_D)}{(C_{L0} - E_D)E_S + E_R}$$

15. The method as defined by claim 14 wherein said step (g) of determining corrupting influences is determined from the expression:

$$C_{L0} = \frac{C_{L1} + \frac{(C_{L2} - C_{L1})}{(C_{L2} - C_{S2})} K_S C_{S0}}{1 + \frac{(C_{L2} - C_{L1})}{(C_{L2} - C_{S2})} K_S}$$

by using both sides of this equation to obtain estimates of Γ_L as set forth in step (f), and testing for the equality of the two estimates.

10 16. The method as defined by claim 8 wherein said step (g) of determining corrupting influences is determined by testing the equality:

$$-z^{-1} = \frac{C_{S1} - E_D}{(C_{S1} - E_D)E_S + E_R}$$

15 17. The method as defined by claim 16 wherein said step (g) of determining corrupting influences is determined by testing the equality:

$$-z^{-2} = \frac{C_{S2} - E_D}{(C_{S2} - E_D)E_S + E_R}$$

18. The method as defined by claim 16 wherein said step (g) of determining corrupting influences is determined by testing the equality:

$$-1 = \frac{C_{S0} - E_D}{(C_{S0} - E_D)E_S + E_R}$$

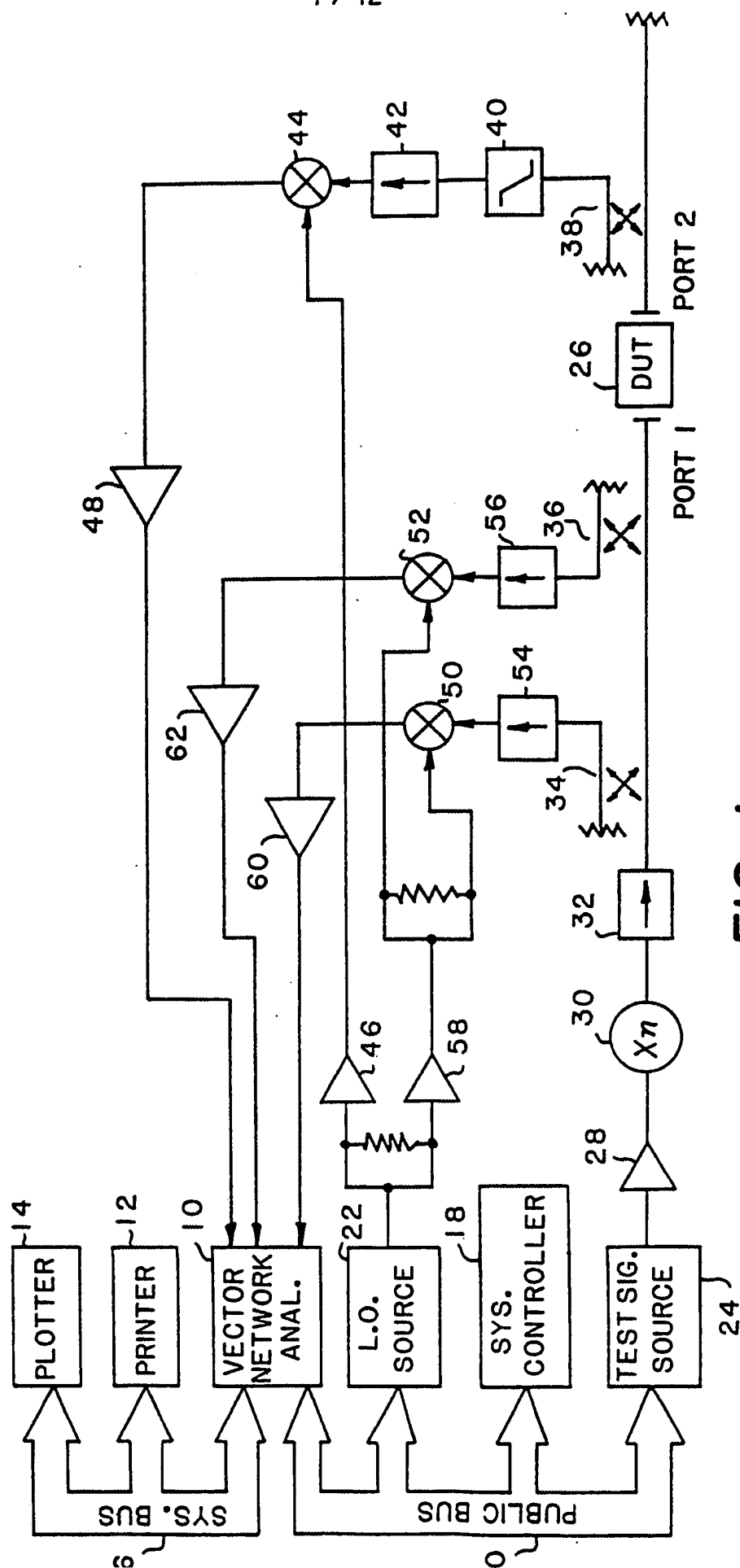


FIG. 1

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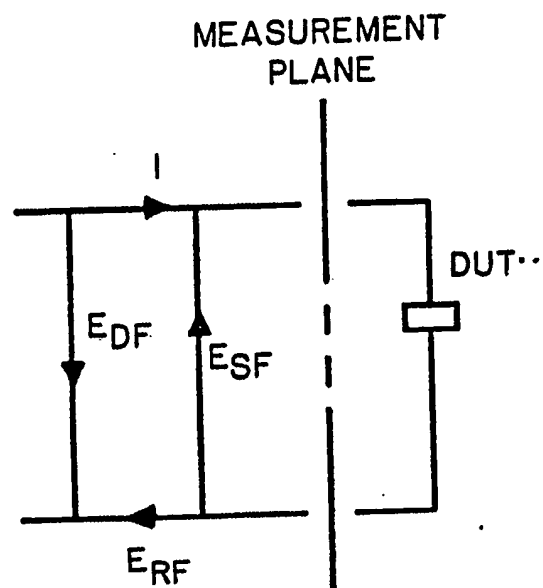


FIG. 2A

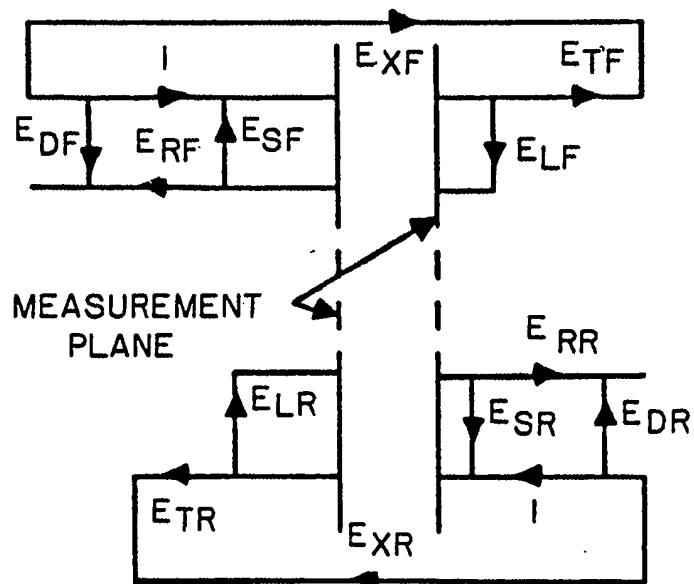
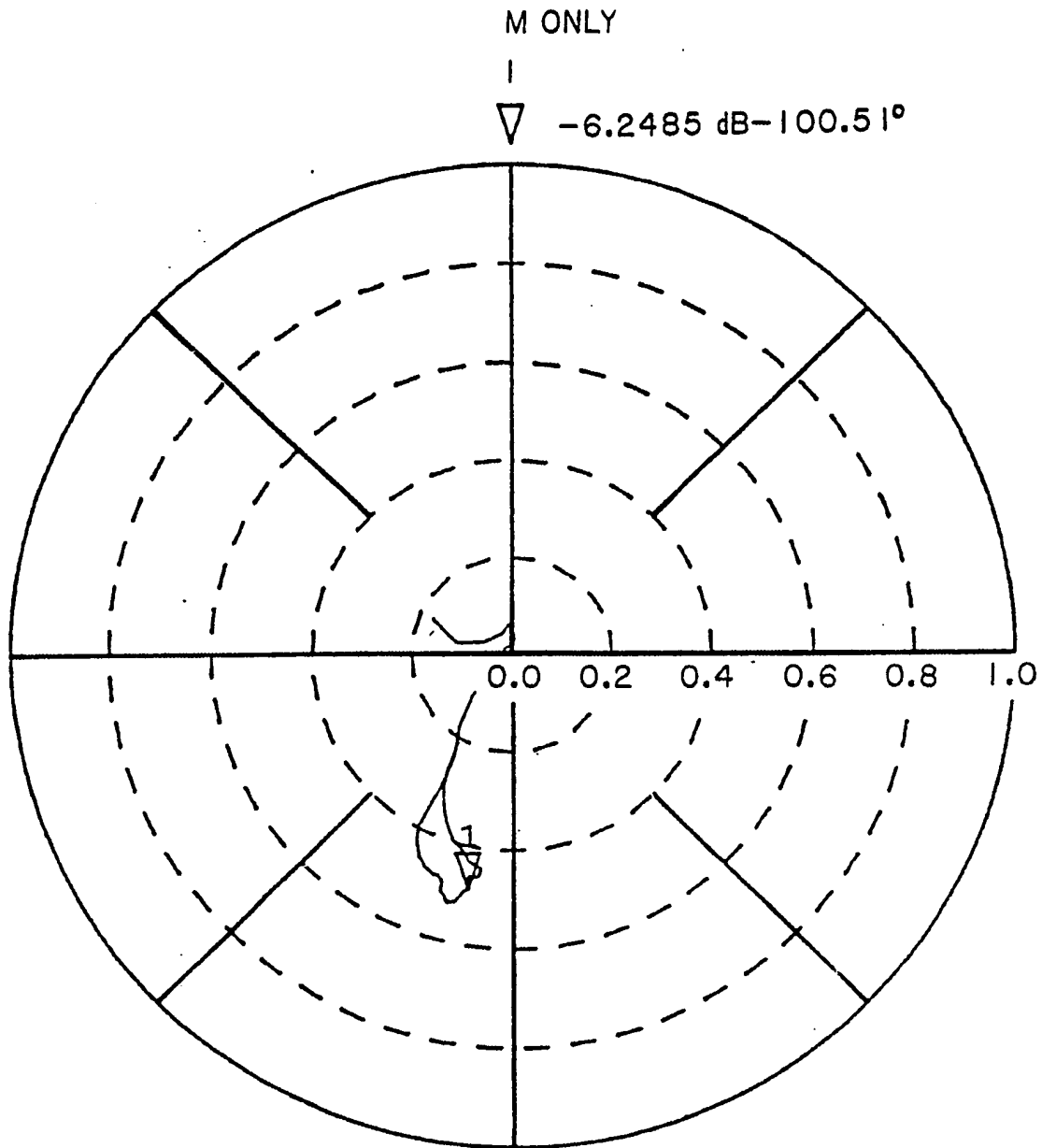


FIG. 2B

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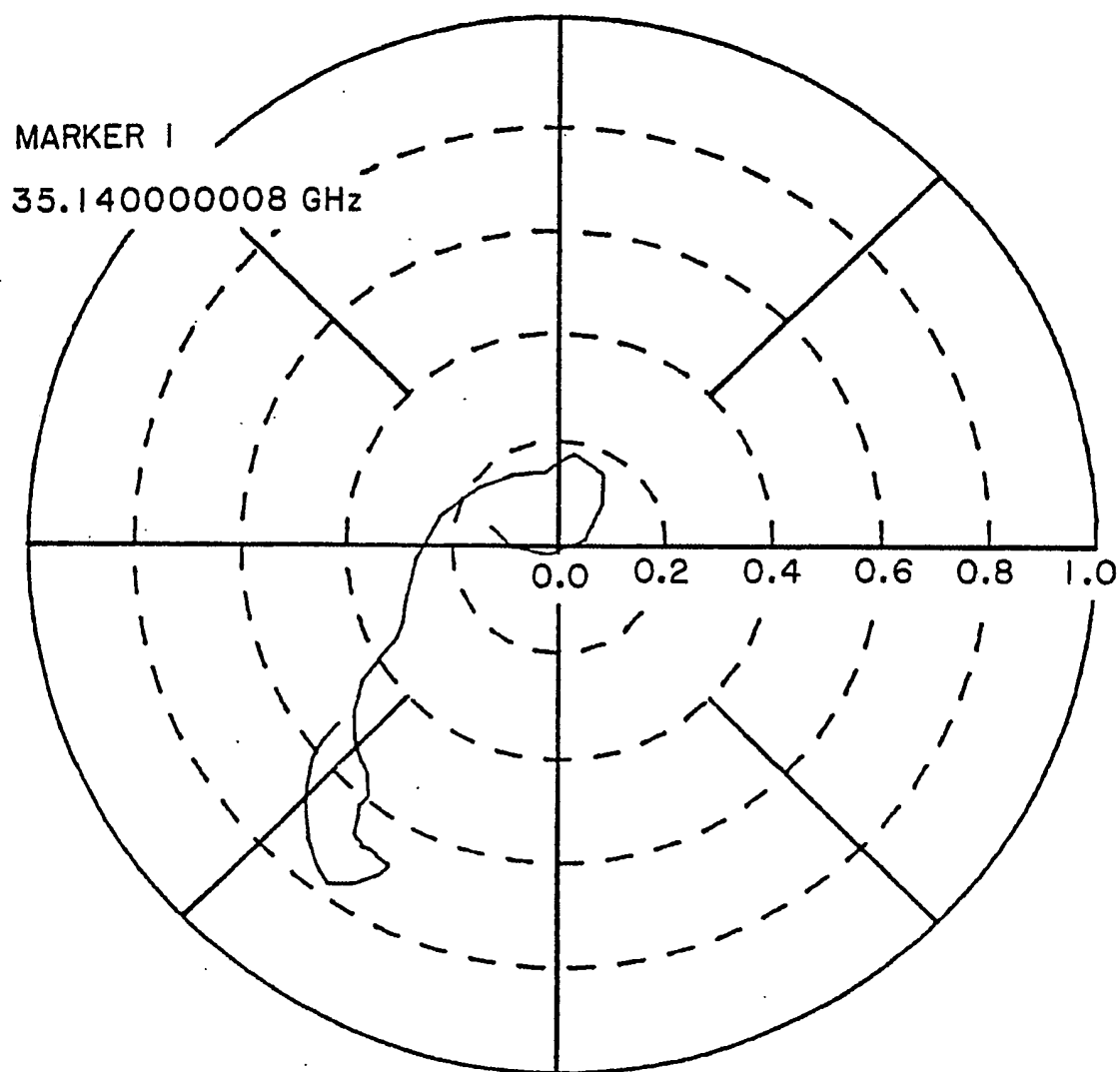


START 26.500000008 GHz
STOP 40.000000008 GHz

FIG. 3

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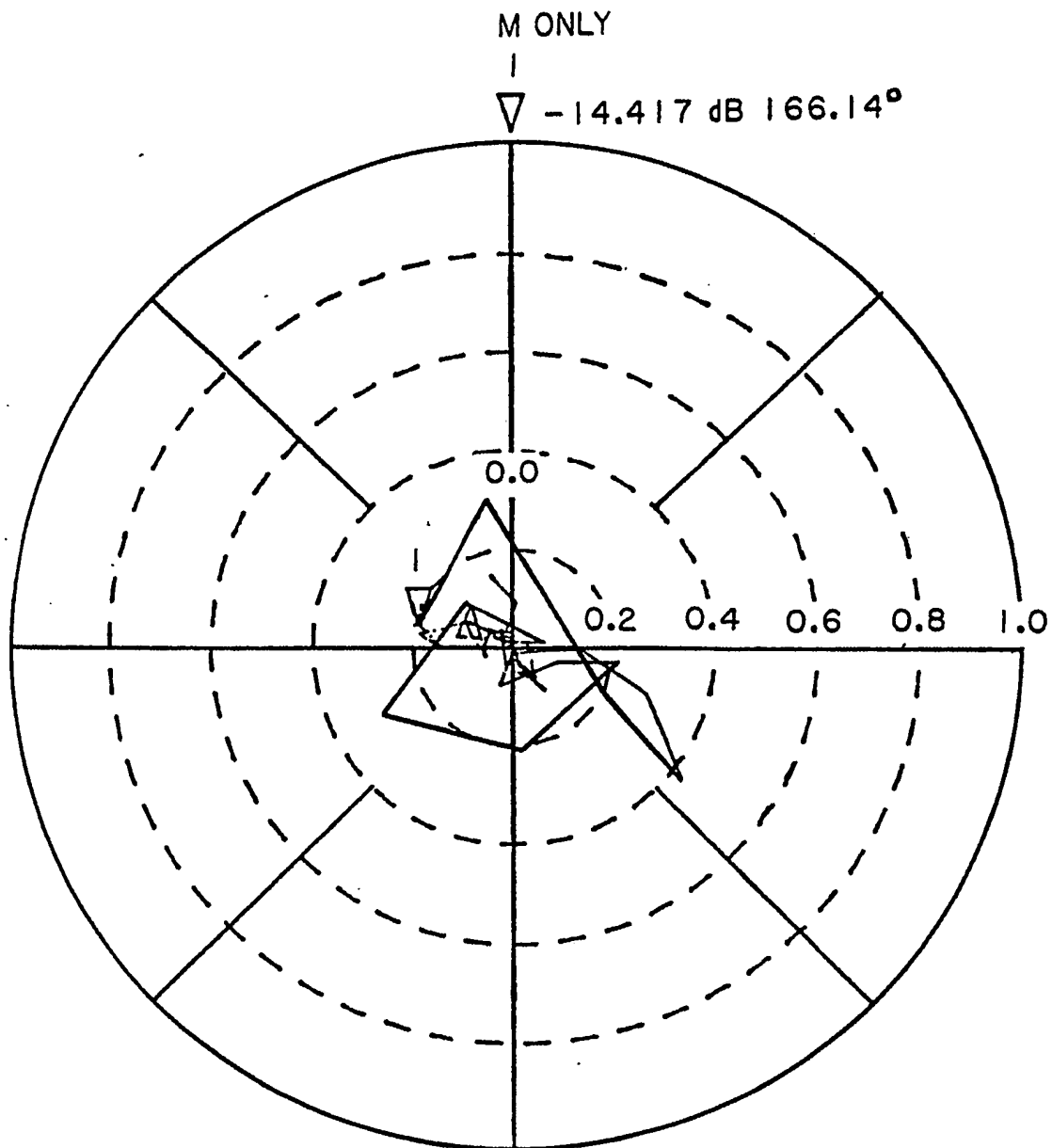
M ONLY



START 26.500000008GHz
STOP 40.000000008 GHz

FIG. 4

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START 26.500000008 GHz
STOP 40.000000008 GHz

FIG. 5

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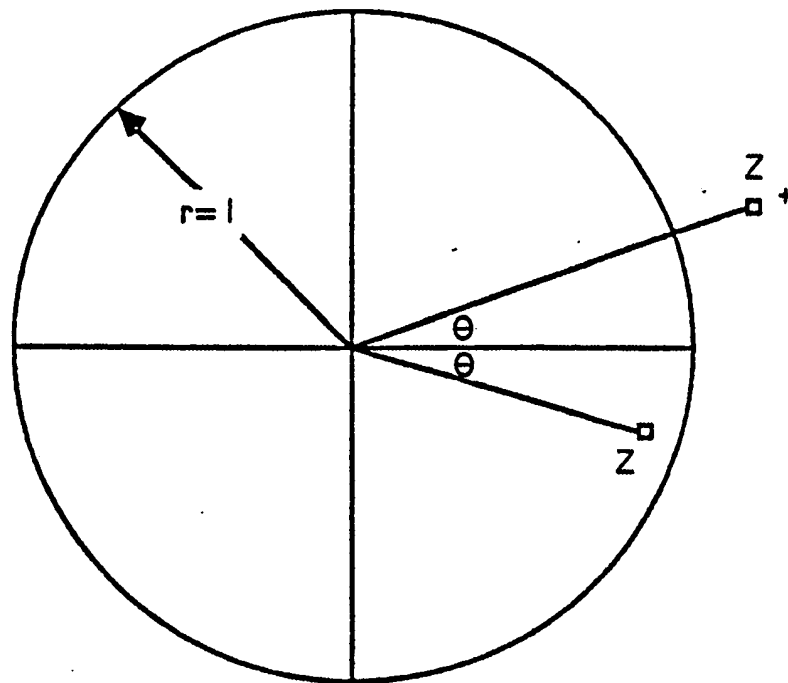


FIG. 6

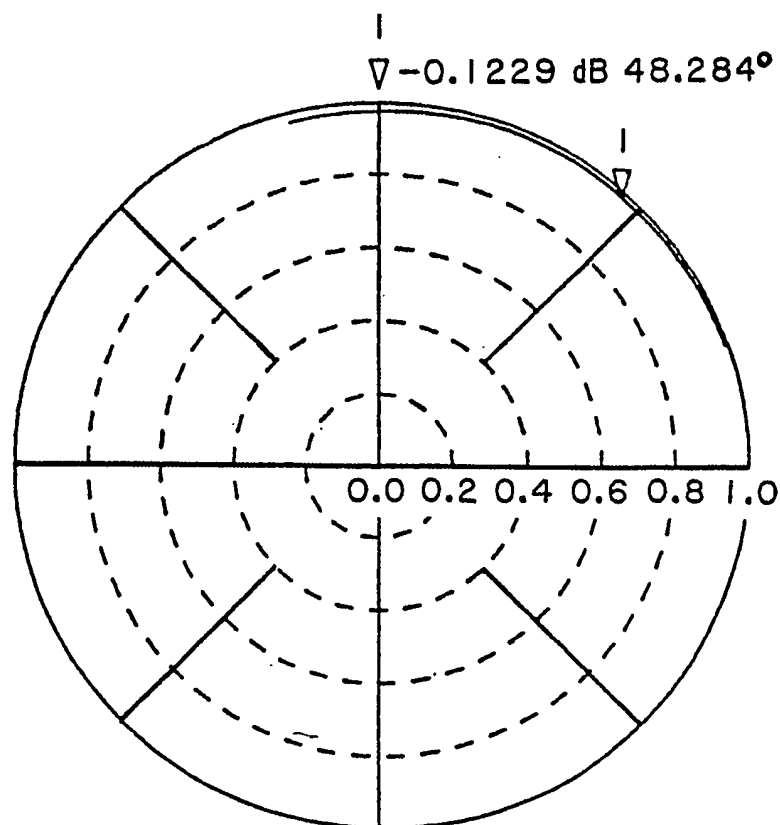


FIG. 7

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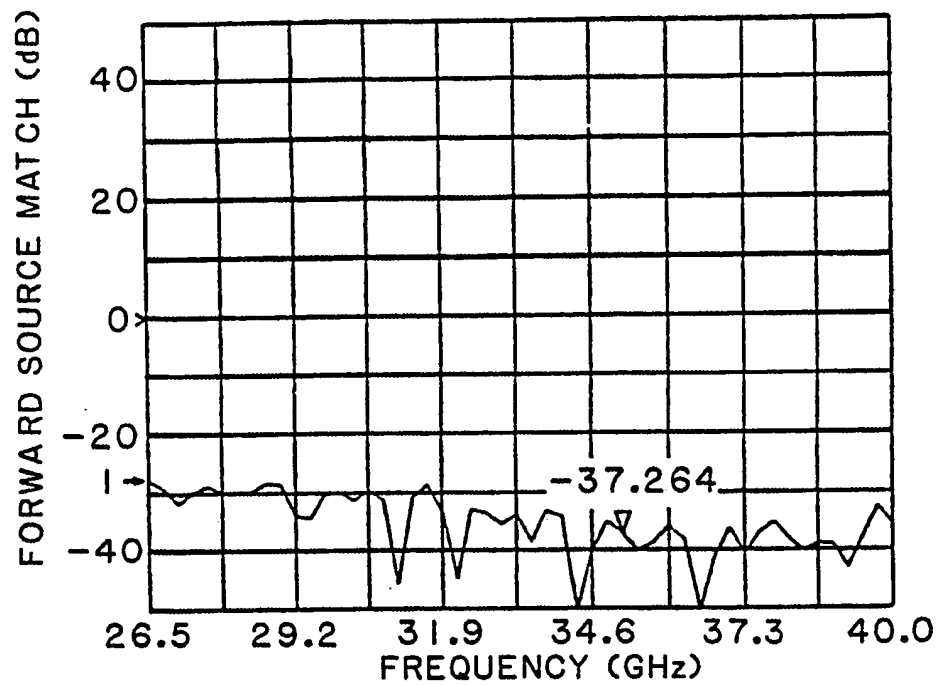


FIG. 8 A

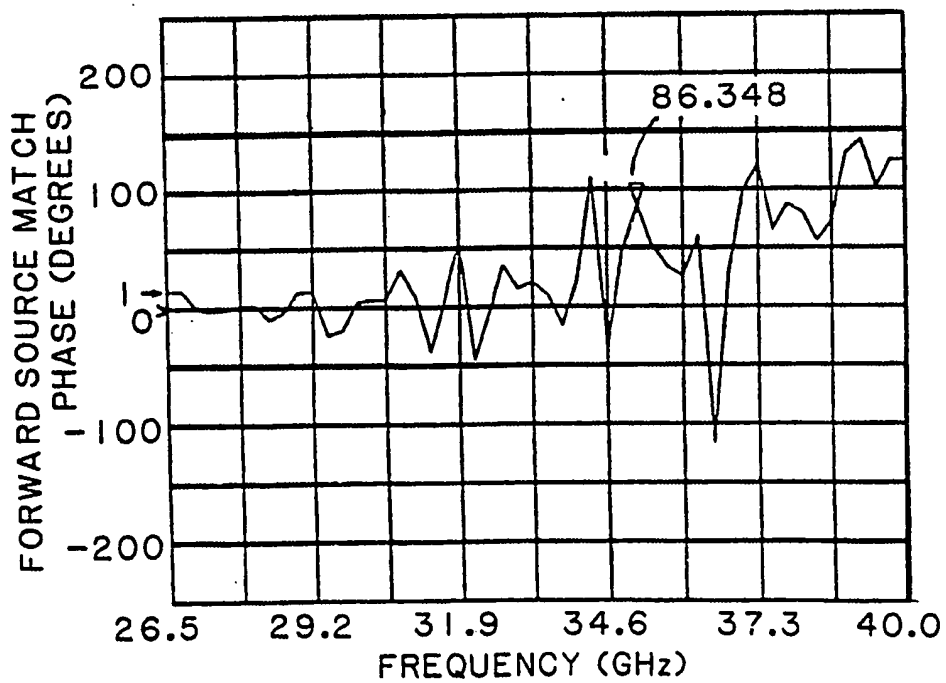


FIG. 8 B

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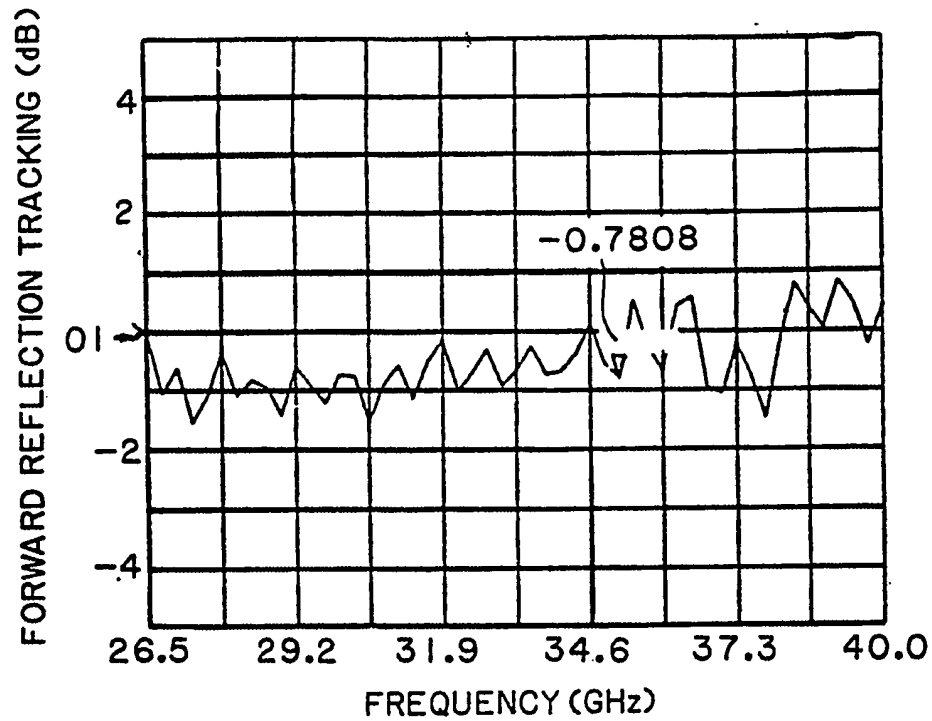


FIG. 9A

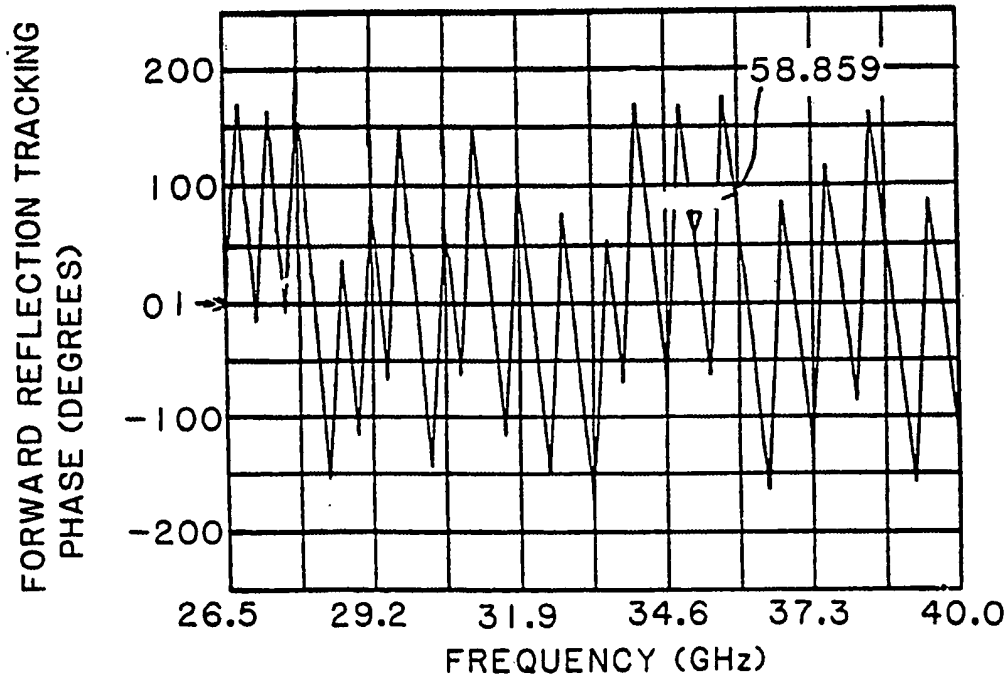


FIG. 9B

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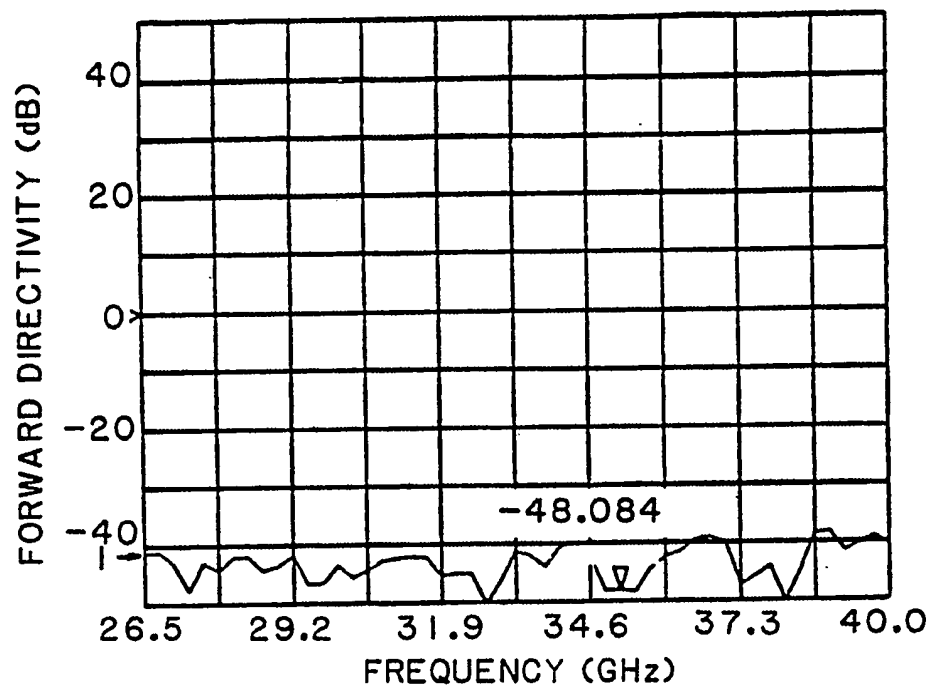


FIG. 10A

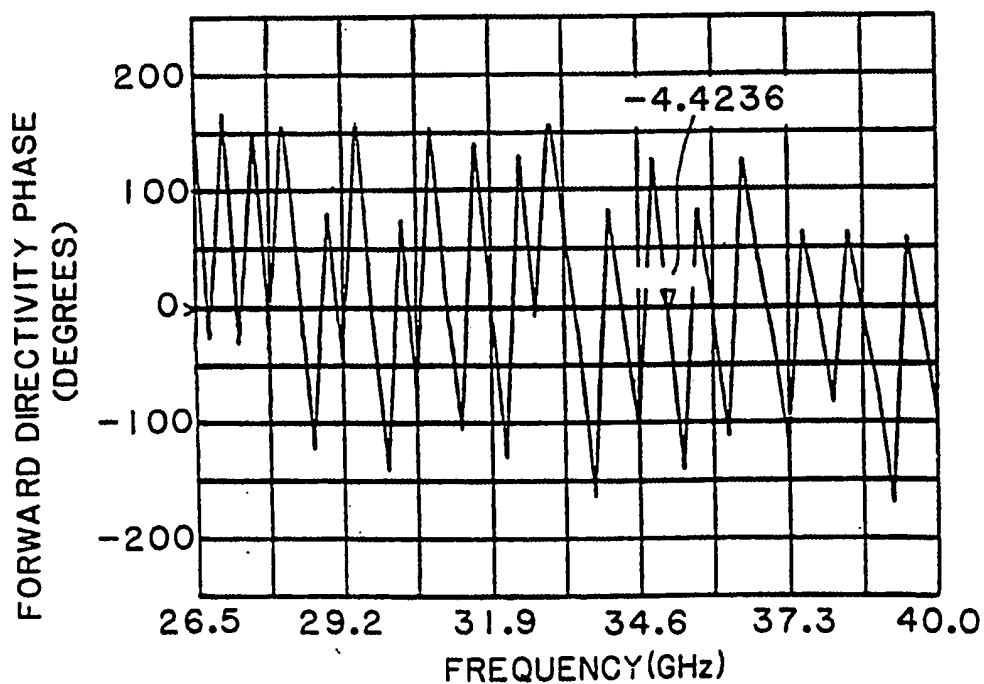


FIG. 10B

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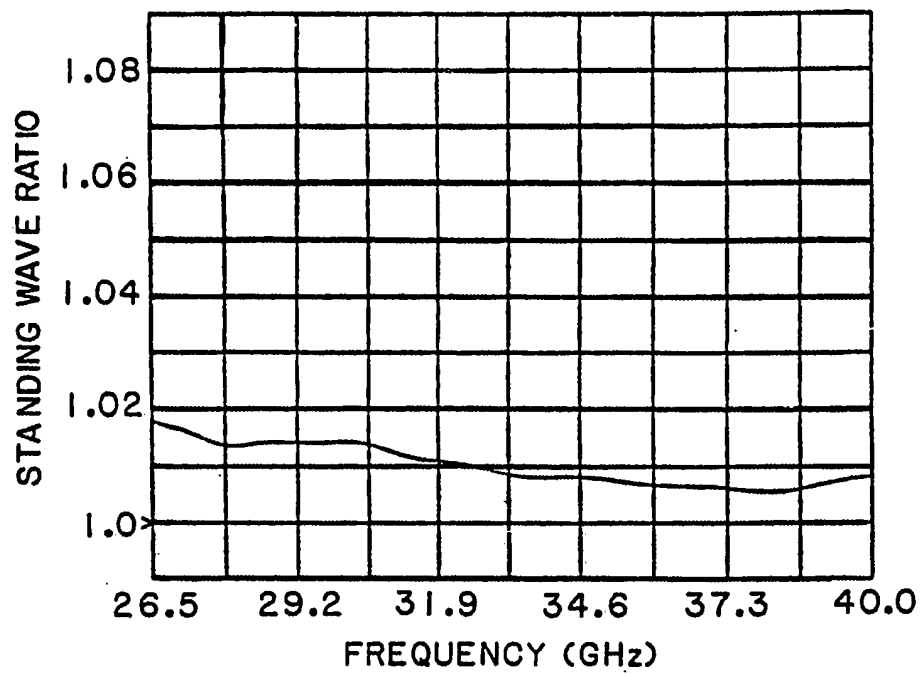


FIG. IIA

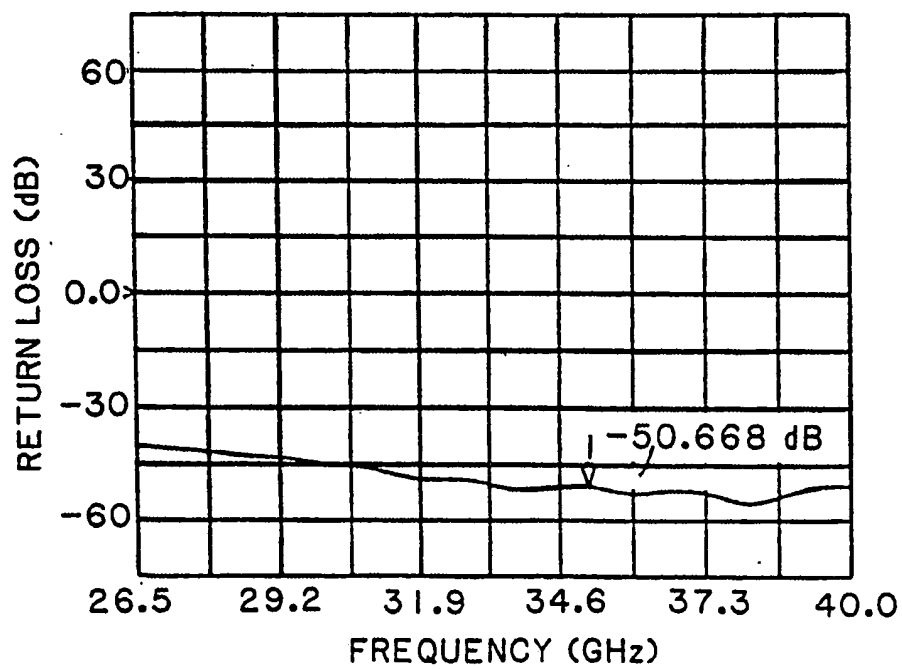
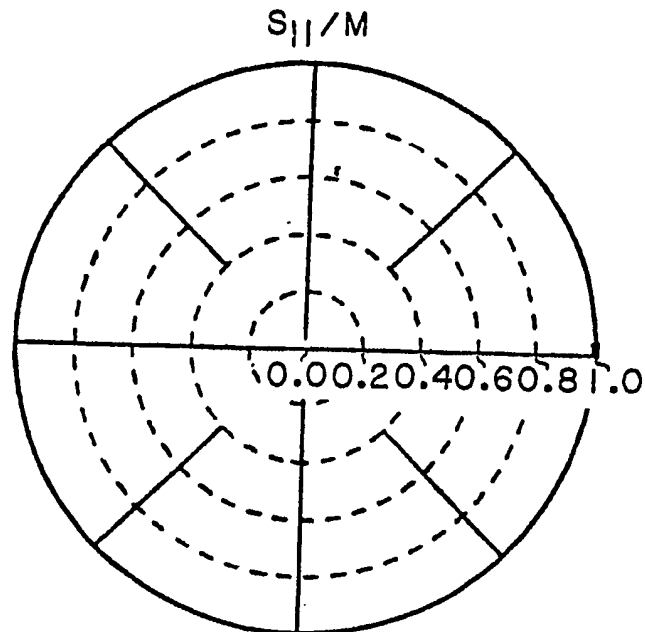
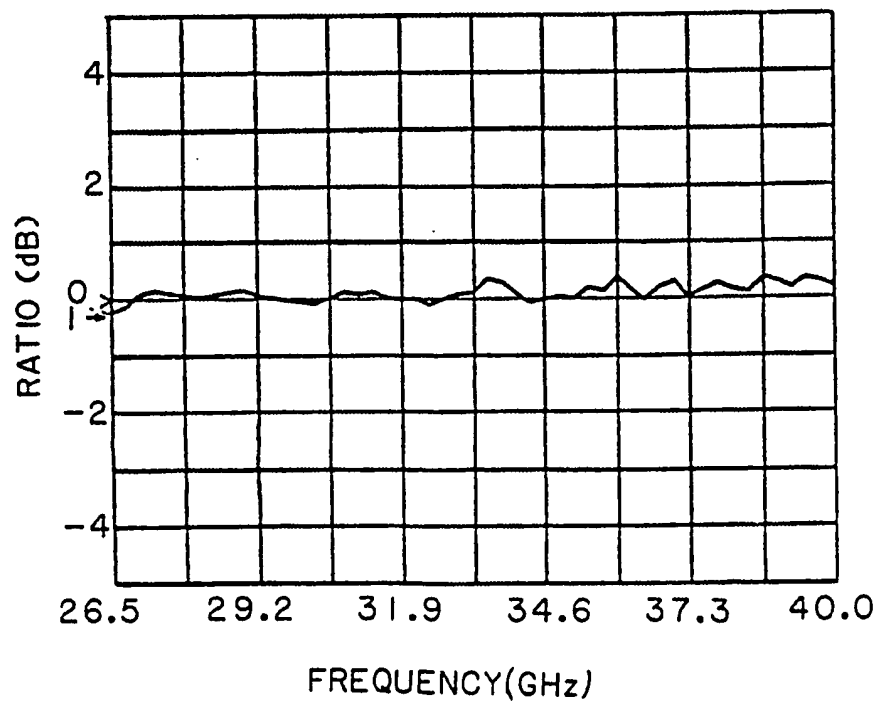


FIG. IIB

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START 26.500000008 GHz
STOP 40.000000008 GHz

FIG. 12**FIG. 13**

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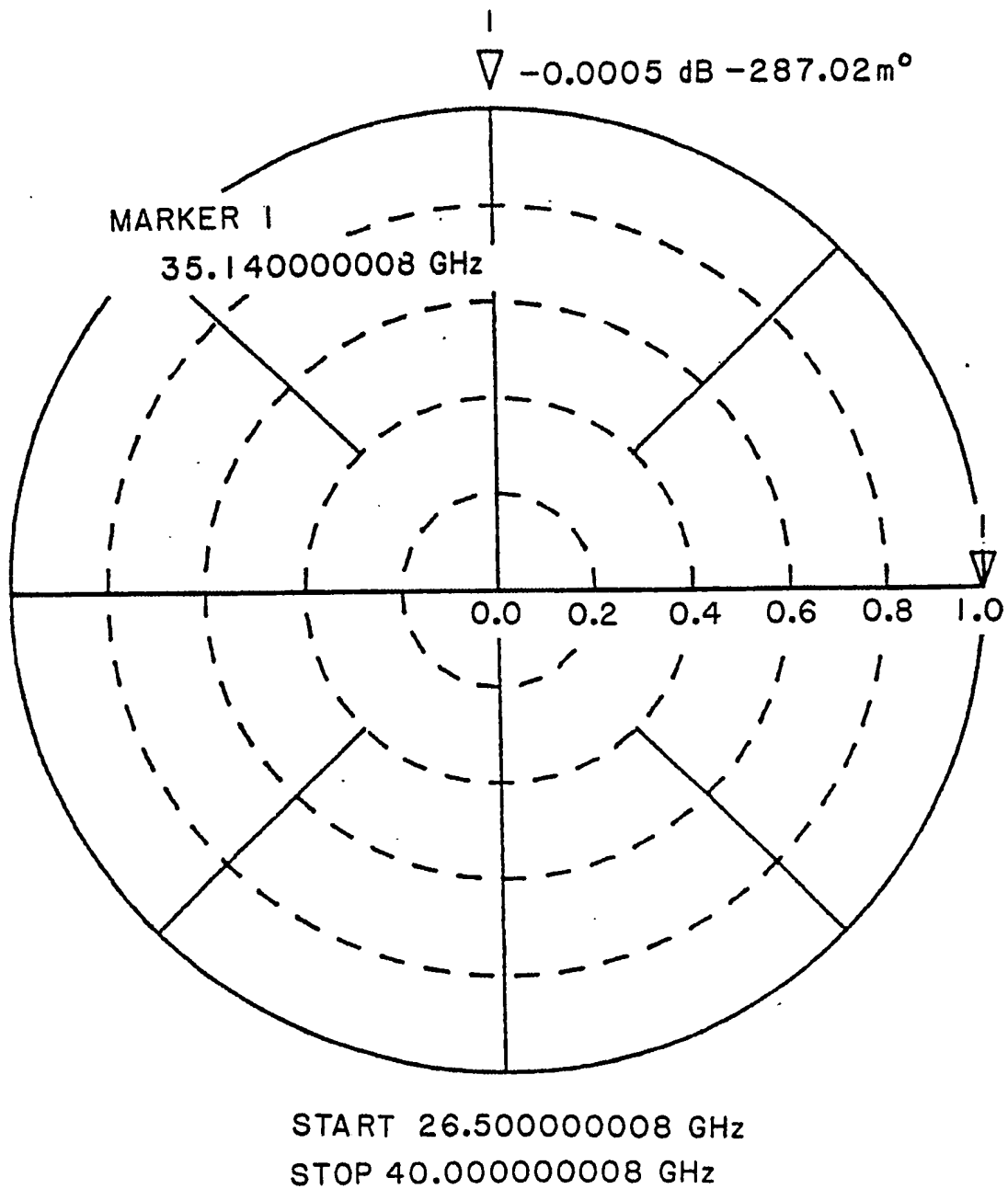


FIG. 14

INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 88/0377

I. CLASSIFICATION OF SUBJECT MATTER (if several classification symbols apply, indicate all) ⁶ According to International Patent Classification (IPC) or to both National Classification and IPC IPC ⁴ : G 01 R 35/00											
II. FIELDS SEARCHED <div style="text-align: right; margin-right: 50px;">Minimum Documentation Searched ⁷</div> <table style="width: 100%; border: none;"> <tr> <td style="width: 30%; border-bottom: 1px solid black; padding-bottom: 5px;">Classification System</td> <td style="border-bottom: 1px solid black; padding-bottom: 5px;">Classification Symbols</td> </tr> <tr> <td style="border: none; padding: 5px;">IPC⁴</td> <td style="border: none; padding: 5px;">G 01 R</td> </tr> </table> <div style="text-align: center; margin-top: 10px; font-size: small;"> Documentation Searched other than Minimum Documentation to the Extent that such Documents are Included in the Fields Searched ⁸ </div>			Classification System	Classification Symbols	IPC ⁴	G 01 R					
Classification System	Classification Symbols										
IPC ⁴	G 01 R										
III. DOCUMENTS CONSIDERED TO BE RELEVANT ⁹ <table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th style="width: 10%; padding: 5px;">Category ⁹</th> <th style="width: 70%; padding: 5px;">Citation of Document, ¹¹ with indication, where appropriate, of the relevant passages ¹²</th> <th style="width: 20%; padding: 5px;">Relevant to Claim No. ¹²</th> </tr> </thead> <tbody> <tr> <td style="text-align: center; vertical-align: top; padding: 5px;">A</td> <td style="padding: 5px;"> The Radio and Electronic Engineer, volume 48, no. 5, May 1978, Institution of Electronic and Radio Engineers, (London, GB), E.F. da Silva et al.: "Calibration of an automatic network analyser using transmission lines of un- known characteristic impedance, loss and dispersion", pages 227- 234 see the whole document cited in the application -- </td> <td style="text-align: center; vertical-align: top; padding: 5px;">1</td> </tr> <tr> <td style="text-align: center; vertical-align: top; padding: 5px;">A</td> <td style="padding: 5px;"> CPEM Digest 1978, Conference on Precision Electromagnetic Measurements, IEEE, (US), B. Bianco et al.: "Calibration procedures for measurements of reflection coefficient", pages 17-19 -- <div style="text-align: right;">./.</div> </td> <td></td> </tr> </tbody> </table>			Category ⁹	Citation of Document, ¹¹ with indication, where appropriate, of the relevant passages ¹²	Relevant to Claim No. ¹²	A	The Radio and Electronic Engineer, volume 48, no. 5, May 1978, Institution of Electronic and Radio Engineers, (London, GB), E.F. da Silva et al.: "Calibration of an automatic network analyser using transmission lines of un- known characteristic impedance, loss and dispersion", pages 227- 234 see the whole document cited in the application --	1	A	CPEM Digest 1978, Conference on Precision Electromagnetic Measurements, IEEE, (US), B. Bianco et al.: "Calibration procedures for measurements of reflection coefficient", pages 17-19 -- <div style="text-align: right;">./.</div>	
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<div style="display: flex; justify-content: space-between; font-size: x-small;"> <div style="width: 45%;"> <p>[*] Special categories of cited documents: ¹⁰</p> <p>"A" document defining the general state of the art which is not considered to be of particular relevance</p> <p>"E" earlier document but published on or after the international filing date</p> <p>"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified).</p> <p>"O" document referring to an oral disclosure, use, exhibition or other means</p> <p>"P" document published prior to the international filing date but later than the priority date claimed</p> </div> <div style="width: 45%;"> <p>"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention</p> <p>"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step</p> <p>"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.</p> <p>"&" document member of the same patent family</p> </div> </div>											
IV. CERTIFICATION <table style="width: 100%; border: none;"> <tr> <td style="width: 50%; border-bottom: 1px solid black; padding-bottom: 5px;">Date of the Actual Completion of the International Search</td> <td style="width: 50%; border-bottom: 1px solid black; padding-bottom: 5px;">Date of Mailing of this International Search Report</td> </tr> <tr> <td style="border: none; padding: 5px;">15th February 1989</td> <td style="border: none; padding: 5px; text-align: right;">08 MAR 1989</td> </tr> <tr> <td style="border-bottom: 1px solid black; padding-bottom: 5px;">International Searching Authority</td> <td style="border-bottom: 1px solid black; padding-bottom: 5px;">Signature of Authorized Officer</td> </tr> <tr> <td style="border: none; padding: 5px; text-align: center;">EUROPEAN PATENT OFFICE</td> <td style="border: none; padding: 5px; text-align: right;"> P.C.G. VAN DER PUTTEN </td> </tr> </table>			Date of the Actual Completion of the International Search	Date of Mailing of this International Search Report	15th February 1989	08 MAR 1989	International Searching Authority	Signature of Authorized Officer	EUROPEAN PATENT OFFICE	 P.C.G. VAN DER PUTTEN	
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15th February 1989	08 MAR 1989										
International Searching Authority	Signature of Authorized Officer										
EUROPEAN PATENT OFFICE	 P.C.G. VAN DER PUTTEN										

III. DOCUMENTS CONSIDÉRÉS COMME PERTINENTS		(SUITE DES RENSEIGNEMENTS INDICUÉS SUR LA DEUXIÈME FEUILLE)
Catégorie *	Identification des documents cités, avec indication, si nécessaire, des passages pertinents	N° des revendications visées
A	1986 IEEE - MTT-S International Microwave Symposium Digest, 2-4 June 1986, Baltimore, Maryland, IEEE, (US), C.A. Hoer et al.: "Calibrating a dual six-port or four-port for measuring two-ports with any connectors", pages 665-668	